


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/710,778	32Qa	
	Examiner	Art Unit	
	Patricia Leith	1655	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBACKFILE updated	7/31/2007	PL
STN: indexed BIOSCIENCE cluster, approx. 76 databases (updated)	7/31/2007	PL
Inventor name search updated EAST/PALM	7/31/2007	PL